

FDZ293P

P-Channel 2.5 V Specified PowerTrench® BGA MOSFET

Features

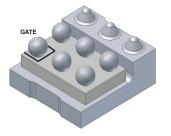
- -4.6 A, -20 V $R_{DS(ON)} = 46 \text{ m}\Omega$ @ $V_{GS} = -4.5 \text{ V}$ $R_{DS(ON)} = 72 \text{ m}\Omega$ @ $V_{GS} = -2.5 \text{ V}$
- Occupies only 2.25 mm² of PCB area. Less than 50% of the area of a SSOT-6
- Ultra-thin package: less than 0.85 mm height when mounted to PCB
- Outstanding thermal transfer characteristics: 4 times better than SSOT-6
- Ultra-low Q_q x R_{DS(ON)} figure-of-merit
- High power and current handling capability.

Applications

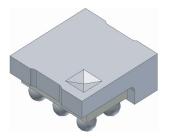
- Battery management
- Load switch
- Battery protection

General Description

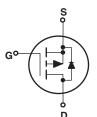
Combining Fairchild's advanced 2.5V specified PowerTrench process with state of the art BGA packaging, the FDZ293P minimizes both PCB space and $R_{\rm DS(ON)}$. This BGA MOSFET embodies a breakthrough in packaging technology which enables the device to combine excellent thermal transfer characteristics, high current handling capability, ultra-low profile packaging, low gate charge, and low $R_{\rm DS(ON)}$.







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Absolute Maximum Ratings $T_A = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter	Ratings	Units	
V _{DSS}	Drain-Source Voltage	-20	V	
V _{GSS}	Gate-Source Voltage	±12	V	
I _D	Drain Current - Continuous	(Note 1a)	-4.6	Α
	- Pulsed		-10	
P _D	Power Dissipation for Single Operation (Note 1a)		1.7	W
T _J , T _{STG}	Operating and Storage Junction Temperature R	-55 to +150	°C	

Thermal Characteristics

F	$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (Note 1a)	72	°C/W

Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape width	Quantity
В	FDZ293P	7"	8mm	3000 units

Electrical Characteristics $T_A = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Charact	eristics		l			
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0V, I_D = -250\mu A$ -20				V
ΔBV _{DSS} ΔT _J	Breakdown Voltage Temperature Coefficient	$I_D = -250\mu A$, Referenced to 25°C		-13		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = -16V, V_{GS} = 0V$			-1	μΑ
I _{GSS}	Gate-Body Leakage.	$V_{GS} = \pm 12V, V_{DS} = 0V$			±100	nA
On Charact	eristics (Note 2)	•		•	•	•
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$	-0.6	-0.8	-1.5	V
$\Delta V_{GS(th)} \ \Delta T_J$	Gate Threshold Voltage Temperature Coefficient	$I_D = -250\mu A$, Referenced to 25°C		3		mV/°C
R _{DS(on)}	Static Drain–Source On–Resistance	$V_{GS} = -4.5V$, $I_D = -4.6A$, $V_{GS} = -2.5V$, $I_D = -3.6A$, $V_{GS} = -4.5V$, $I_D = -4.6A$, $T_J = 125^{\circ}C$, = -3.6A,		46 72 65	mΩ
I _{D(on)}	On-State Drain Current	$V_{GS} = -4.5V, V_{DS} = -5V$	-10			Α
9 _{FS}	Forward Transconductance	$V_{DS} = -5V, I_{D} = -4.6A$		13		S
Dynamic Ch	naracteristics	•		•	•	•
C _{iss}	Input Capacitance	$V_{DS} = -10V, V_{GS} = 0V,$		754		pF
C _{oss}	Output Capacitance	f = 1.0MHz		167		pF
C _{rss}	Reverse Transfer Capacitance			92		pF
R _G	Gate Resistance	V _{GS} = 15mV, f = 1.0MHz		6		Ω
Switching C	Characteristics (Note 2)					
t _{d(on)}	Turn-On Delay Time	$V_{DD} = -10V, I_D = -1A,$		11	20	ns
t _r	Turn-On Rise Time	$V_{GS} = -4.5V$, $R_{GEN} = 6\Omega$		10	20	ns
t _{d(off)}	Turn-Off Delay Time			22	35	ns
t _f	Turn-Off Fall Time			17	31	ns
Q _g	Total Gate Charge	$V_{DS} = -10V, I_D = -4.6A,$		7.5	11	nC
Q _{gs}	Gate-Source Charge	V _{GS} = -4.5V		1.5		nC
Q _{gd}	Gate-Drain Charge			2.0		nC

Electrical Characteristics T_A = 25°C unless otherwise noted (Continued)

Drain-Source Diode Characteristics and Maximum Ratings						
I _S	Maximum Continuous Drain-Source Diode Forward Current -1.4 A I _S			I _S		
V_{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0V, I_S = -1.4A$ (Note 2)		-0.7	-1.2	V
t _{rr}	Diode Reverse Recovery Time	$I_F = -4.6A$,		17		nS
Q _{rr}	Diode Reverse Recovery Charge	$d_{iF}/d_t = 100A/\mu s$		5		nC

Notes:

1. $R_{\theta JA}$ is determined with the device mounted on a 1 in² 2 oz. copper pad on a 1.5 x 1.5 in. board of FR-4 material. The thermal resistance from the junction to the circuit board side of the solder ball, $R_{\theta JB}$, is defined for reference. For $R_{\theta JC}$, the thermal reference point for the case is defined as the top surface of the copper chip carrier. $R_{\theta JC}$ and $R_{\theta JB}$ are guaranteed by design while $R_{\theta JA}$ is determined by the user's board design.



a) 72°C/W when mounted on a 1in2 pad of 2 oz copper, 1.5" x 1.5" x 0.062" thick PCB



b) 157°C/W when mounted on a minimum pad of 2 oz copper

2. Pulse Test: Pulse Width < 300µs, Duty Cycle < 2.0%

Typical Characteristics

-50

-25

0 25

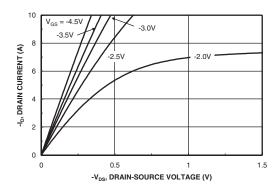


Figure 1. On-Region Characteristics.

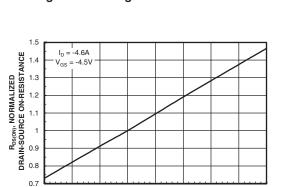


Figure 3. On-Resistance Variation with Temperature.

50

 T_J , JUNCTION TEMPERATURE (°C)

75

100

125

150

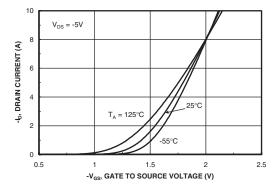


Figure 5. Transfer Characteristics.

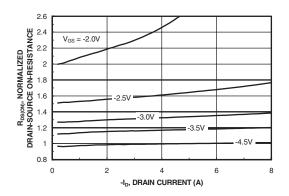


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

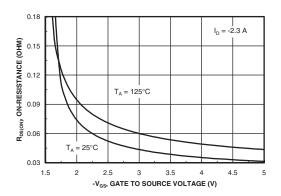


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

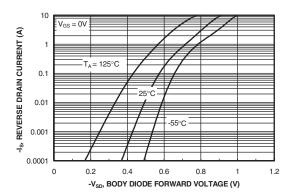


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics

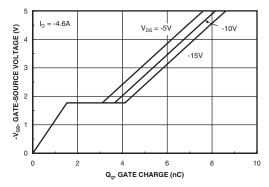


Figure 7. Gate Charge Characteristics.

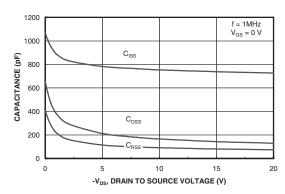


Figure 8. Capacitance Characteristics.

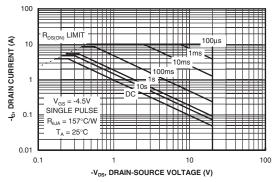


Figure 9. Maximum Safe Operating Area.

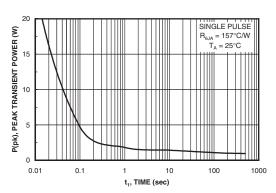


Figure 10. Single Pulse Maximum Power Dissipation.

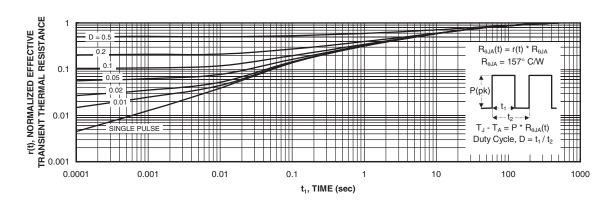
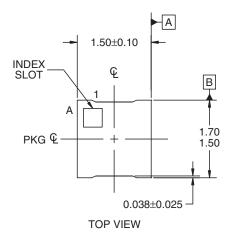


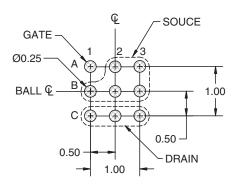
Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1b. Transient thermal response will change depending on the circuit board design.

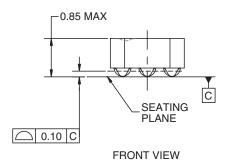
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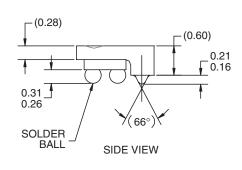
Dimensional Pad and Layout

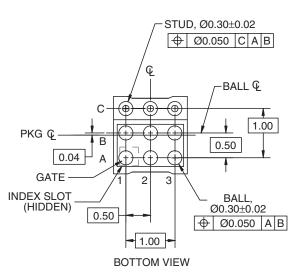




LAND PATTERN RECOMMENDATION







NOTES: UNLESS OTHERWISE SPECIFIED

- A) ALL DIMENSIONS ARE IN MILLIMETERS.
- B) NO JEDEC REGISTRATION REFERENCE AS OF SEPTEMBER 2003.
- C) BALL/STUD CONFIGURATION TABLE

TERMINAL ID	DESIGNATION	TERMINAL TYPE
C1,C2,C3	DRAIN	COPPER STUD
A1	GATE	BALL
A2,A3,B1,B2,B3	SOURCE	

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Definition of Terms

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